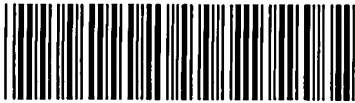


Search Notes

Application/Control No.

10/538,715

Examiner

Taeyoon Kim

Applicant(s)/Patent under
Reexamination

FARDEAU ET AL.

Art Unit

1651

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST search (USPG-pub;USPAT;USOCR;EPO;JPO;Derwent)	6/11/2007	TK
Inventor search (PALM)	6/11/2007	TK
BLAST search (NCBI)	6/11/2007	TK